

Dpt MicroElec. MicroCapt.

Titre :

Sur l'utilisation de la résine UV210 se flashant en UV profond pour les circuits de photonique intégrée / optoélectroniques : processus de nano-lithographie, propriétés physiques et structures réalisées

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+ Plate forme NanoRennes : <u>https://www.ietr.fr/plateforme-nr-nanorennes</u>



*<u>https://www.ietr.fr/bruno-beche</u> https://spm.univ-rennes1.fr/bruno-beche







A 883

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Campus Sciences

et Philosophie

756

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> 200 bilateral agreements with European universities 32 Institutes of Research (CNRS, INRA, INSERM...)

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▶ 15 DUT

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- 45 mentions de Master
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- Diplômes de santé
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Sciences, Ingénierie & Technologies

Droit, économie, gestion et SHS



Context - Mastery of Technologies (NanoRennes_IETR CNRS)





Materials and Processes - 'past for us'

Choices and study of organic materials, many products and liquid photoresist exist for the realizations of integrated elements [PMMA, PS233, SU8, NOA stick, Kapton...] for μ -fluidic, photonics, optoelectronics...

- Photolithography: limited by diffraction
- Usual lithography: insolation at λ = 365 nm
- Limit of 'clean' resolution *close to 1 μm* (difficult when thick resin !)



• Example with resins flashing at 365 nm or 'non-simplicity' to build a 2.5D micro-resonator





• For 2.5D structures, existence of a surface energy or surface tension γ which can make difficult all possible and unimaginable assemblies \rightarrow Surface energy modification and measurements (J.m⁻²) : [$\gamma = (\partial G/\partial S)_{T,p,n}$]

Possibility of modifying it by plasma surface treatment, modifying the adhesion work $W_{material1/material2}$ which is *function of* γ





Not in one step and so simple !





- The Deep UV lithography (DUV):
- Insolation at λ = 248 nm
 Organic material DUV 210 (positive photoresist)
- High resolution: 200 nm → quartz mask



Chemical aspect :

UV210 is a chemically amplified (CA) resin based on poly p-hydroxystyrene (PHS) in combination with poly t-butyl acrylate (PBA). Such a CA resin contains a photo-acid generator (PAG), added to the copolymer matrix. When exposed to deep-UV light (248 nm), *PAG produces a small amount of acid which acts as a catalyst* during post-baking exposure. *The cascade of chemical transformations* activated by the acid results in a change in polarity in the polymer from lipophilic to hydrophilic.

- Judicious optical properties

n=1.565 + lower optical losses (typically 3 dB.cm⁻¹ at λ = 980nm)





Materials and Processes

Photolithography: Deep_UV 210 (with development ridge, rib or not photo-inscripted)

Steps	Parametres
Spin-coating (v,a,t), thickness, roughness	(900 rpm, 5000rpm/s, 30s), ~800-850 nm, <3 nm
Softbake	3 min at 140°C
Deep UV exposure	$E = 20 \text{ mJ/cm}^2 \text{ during } 27 \text{ s}$
Post-exposure soft-bake	1 min at 120°C
Development	30 s, with Microposit MF CD-26
Final softbake	12 to 24 h at 120°C







Materials and Processes

- The UV210 organic material
- Ellipsometric measurement & dispersion curves of UV210 (extinction k <10⁻³)



 Indices enough high for core waveguide applications on lower cladding

Insolation dose increases : saturation of the value of index and diminution of film thickness, density increases (Gladstone empiric law)







Insolation dose effect : diminution of film thickness, density increases

AFM measurement



Dotted shape photo-inscripted (before development here)



- Possibility to develop sub- λ patterns of Deep UV210 for nanotechnology

Width of waveguide 250/300 nm





+ Good mechanical strength when hardened



18m F1 L01 .000 15mm



Quality control : AFM imaging





Roughness surface : 2 nm

0

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• Quality control / Raman Spectroscopies analyses + Imaging



Raman spectroscopies *plus* Imaging reconstruction



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Optical transparency and single mode guiding



- An example of schematic curved structure shaped/developed with only one layer/flash !





Thank you for your attention



Références

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